



Cascade

Probe Positioners

DC, RF and Optical Probe Positioning for Highest Accuracy Measurements





DC, RF and Optical Probe Positioning for Highest Accuracy Measurements



Highest accuracy with backlash-free positioning

Best signal integrity using optimized probe cabling systems

Drift-free measurements over temperature and time*

Full thermal capability*

Easy, and safe swapping between arms

Manual or progammable

FormFactor offers a wide variety of manual and motorized probe positioners for any application from DC to terahertz measurements and beyond.

Engineered for high stability and accuracy, FormFactor's positioners enable precise, backlashfree and repeatable probe tip placements - from simple IV/CV measurements to highly challenging measurement tasks.

Enhanced with FormFactor's **High Thermal Stability** (HTS), the positioners become part of our exclusive **Contact Intelligence™ Technology** that enables small pad probing over a full temperature range of -60°C to 300°C.

Unsurpassed accuracy and highest productivity is achieved with the revolutionary **Autonomous**Measurement Assistants for DC, RF and Silicon Photonics testing. These wafer probing assistants utilize our programmable positioners and enable fully

autonomous, hands-free measurements – minimizing training needs and accelerating time to market.

Designed and validated with proven quality standards, our positioners are always the perfect match to your FormFactor probe system.

Application Flexibility

/ Device Characterization and Modeling

/ Ultra-low Noise Measurements (1/f)

/ RF, mm-Wave and Terahertz Measurements

/ High Power Test

/ Failure Analysis

/ Silicon Photonics Measurements

/ MEMS Test

*With HIgh Thermal Stability (HTS).

Manual DC Probe Positioners

DPP105	
Probe technology	Use with PTT DC probe needles
Feature resolution	5 μm
Travel range (X/Y/Z)	8 / 6 / 25 mm
Mounting	Vacuum, magnetic
Footprint (WxD)	60 mm x 20 mm
Applications	Basic IV probing
	Ideal for applications that require more than eight positioners

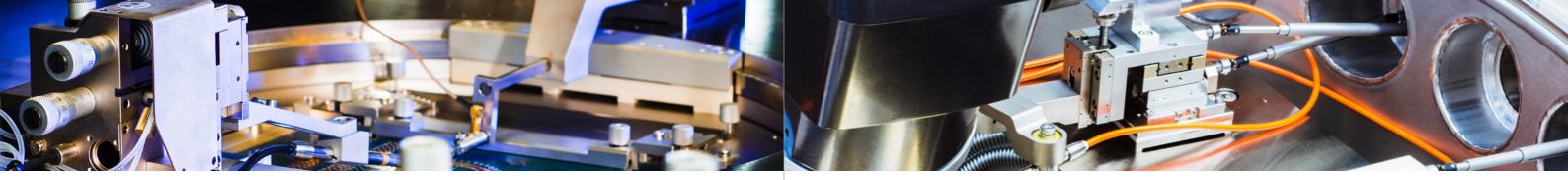


DPP205 / DPP210 / DPP220

Probe technology	Use with DCP high performance DC probes					
Feature resolution	<2 μm (DPP205) / <1 μm (DPP210) / 0.5 μm (DPP220)					
Travel range (X/Y/Z)	12.5 / 12.5 mm / 12.5 mm					
Mounting	Vacuum, magnetic					
Footprint (W x D)	90 mm x 60 mm					
Application	IV/CV probing					
	Failure analysis					



For station compatibility see last page. For detailed specifications see the Probe Station Accessory Catalog.



Manual DC Probe Positioners (Continued)

DPP305 / DPP310						
Probe technology	Use with DCP high performance DC probes					
Feature resolution	0.5 μm					
Travel range (X/Y/Z)	10 mm / 10 mm / 8 mm					
Mounting	Vacuum, magnetic					
Footprint (WxD)	75 mm x 50 mm					
Applications	High-precision and high-resolution probing					
	High-performance IV/CV probing and failure analysis					
	Internal node probing					



Probe technology Feature resolution Travel range (X/Y/Z) Mounting Vacuum, magnetic Footprint (W x D) Application High-resolution probing High-performance IV/CV probing and failure analysis High-performance internal node probing



Manual Vacuum/Cryogenic Probe Positioner

VCP110	
Probe technology	Use with high performance DC or RF probes
Feature resolution	3 μm
Travel range (X/Y/Z)	12 mm / 12 mm / 12 mm
Mounting	Magnetic
Footprint (WxD)	65 mm x 65 mm
Applications	IV/CV/RF probing and failure analysis in vacuum/cryogenic environment

For station compatibility see last page. For detailed specifications see the Probe Station Accessory Catalog.



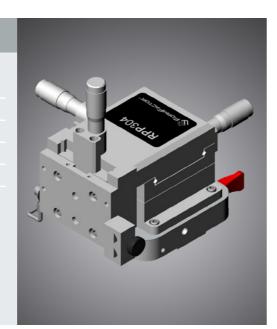


Manual RF Probe Positioners

RPP210				
Probe technology	Use with Infinity / ACP / Z Probe high performance RF probes			
Feature resolution	<1 µm			
Travel range (X/Y/Z)	12.5 mm / 12.5 mm / 12.5 mm			
Mounting	Vacuum, magnetic			
Footprint (W x D)	90 mm x 60 mm			
Application	RF and multi-contact/ mixed-signal probing			
	Wafer-level reliability probing			



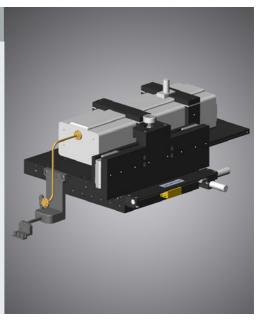
RPP304				
Probe technology	Use with Infinity / ACP / IZI Probe / T-Wave high performance RF probes			
Feature resolution	<1 µm			
Travel range (X/Y/Z)) 12 mm / 12 mm / 12 mm			
Mounting	Bolt down			
Footprint (WxD)	133 mm x 147 mm			
Applications	High-performance RF, multi-contact/mixed signal probing			
	High-performance wafer-level reliability probing			
	Single-ended broadband/ mm-Wave, terahertz, source/load-pull, RF noise probing			



RPP305					
Probe technology	Use with Infinity / ACP / IZI Probe / T-Wave high performance RF probes				
Feature resolution	<1 µm				
Travel range (X/Y/Z)	25 mm / 25 mm / 10 mm				
Mounting	Bolt down				
Footprint (W x D)	124 mm x 124 mm				
Application	High-performance RF, multi-contact/mixed signal probing				
	High-performance wafer-level reliability probing				
	Single-ended broadband/ mm-Wave, terahertz, source/load-pull, RF noise probing				



mmW Large Area Positioner						
Probe technology	Use with Infinity / ACP / T-Wave high performance RF probes					
Feature resolution	3 μm					
Travel range (X/Y/Z)	150 mm / 150 mm / 12.5 mm					
Mounting	Bolt down 204 mm x 204 mm					
Footprint (W x D)						
Application	High-performance single-ended/differential broadband/ mm-Wave, sub-THz S-parameters, source/ load-pull, RF noise					



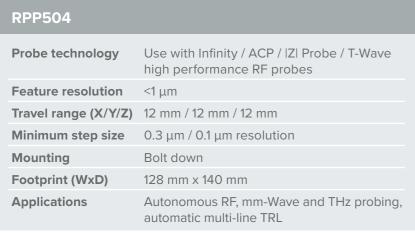
For station compatibility see last page. For detailed specifications see the Probe Station Accessory Catalog.

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Motorized RF Probe Positioner RPP504 for Autonomous RF, mm-Wave and Terahertz Measurements



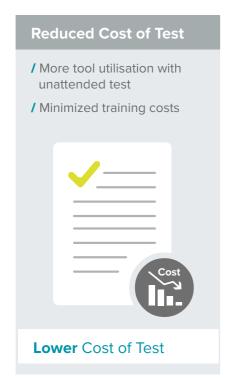




The RPP504 is part of FormFactor's revolutionary **Autonomous RF Measurement Assistant****, which enables fully autonomous, hands-free RF calibrations and measurements over multiple temperatures.

Featuring the exclusive Contact Intelligence™ Technology, it significantly reduces cost of test and accelerates time to market with increased accuracy and reduced design cycles.

/ More modelling data with increased accuracy and reduced uncertainty IC Design IC Test Fewer Design Cycles





Motorized HexNano Probe Positioner for Autonomous Silicon Photonics Measurements

VIDEO

FormFactor offers a completely integrated and validated solution for Silicon Photonics measurements at wafer level*. Our Autonomous SiPh Measurement Assistant is supported by our unique Contact Intelligence™ Technology and enables you to measure your photonic devices in days instead of months or years — without further development.

Part of our solution is the HexNano positioner with a precision XYZ piezo positioner and high rigidity space frame fiber arms.

Industry-First Features

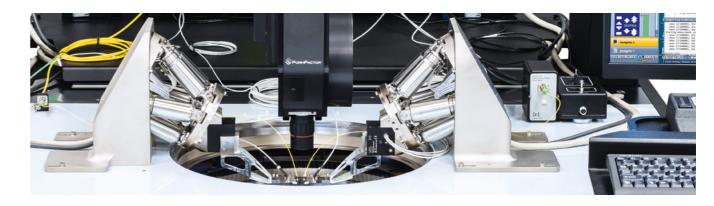
/ Validated Integration

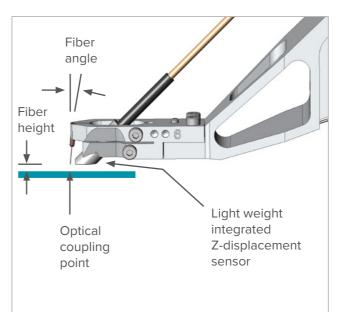
/ Verified Performance

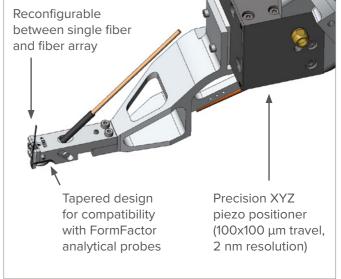
/ Automated Calibrations and Alignments

/ Integrated Z-Displacement

/ Reconfigurable Fiber Arms with Light Guide Technology

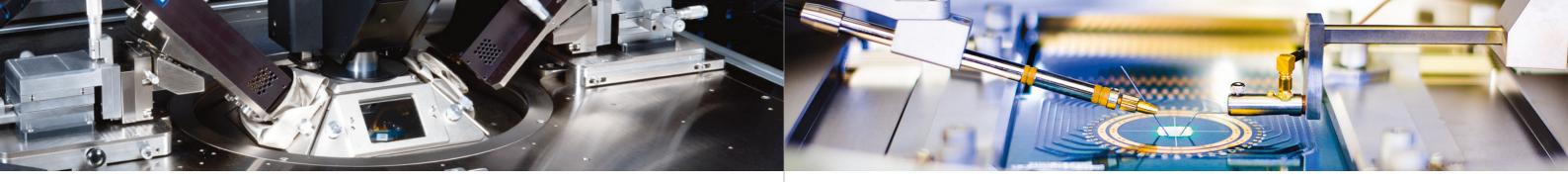






*Available for CM300xi and SUMMIT200.

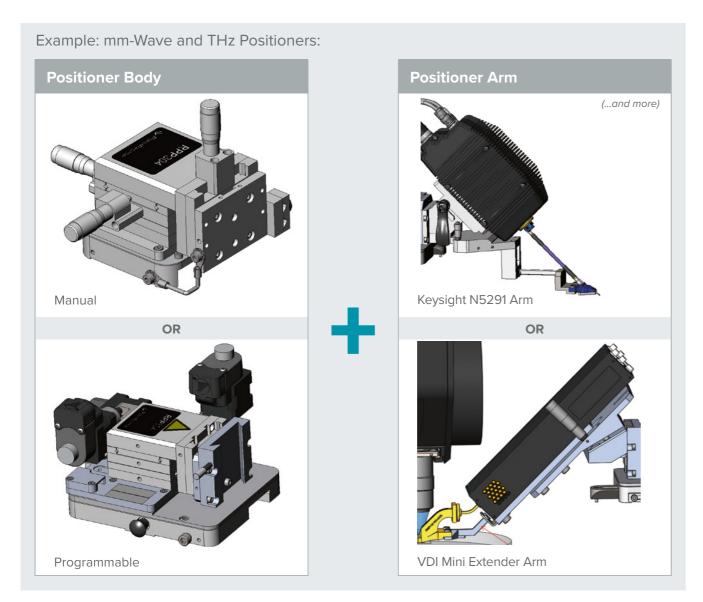
^{*} Available for CM300xi, SUMMIT200 and Elite 300.



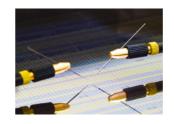
Easy Swapping Between Probe Arms

Our positioners are highly flexible, and with the corresponding positioner arms they are the perfect match to your FormFactor probe station. Intuitive installation and easy swapping between different positioner arms reduces training needs and leads to faster time to test.

In particular, our positioners for RF, mm-Wave and THz measurements are completely modular. You can simply choose between a manual or programmable positioner body and add a specific arm (for example VDI Mini Extender Arm or Keysight N5291 Arm). The arms are equipped with a dove tail that makes it easy, safe and fast to change between different bands.



Probe Arms









General CV/IV Arms

- / Basic Coax/Triax measurements down to pA-level
- / PTT needles
- / Applications:
 Failure analysis, Device characterization and modelling

Dedicated High Voltage/Current Arms

- / On-wafer power device characterization up to 10,000 V DC / 600 A
- / Increased isolation resistance and dielectric strength to provide full triaxial capability at high voltage (3,000 V) for low-leakage measurement
- / Full temperature range of -55 to 300°C
- / Highest safety for the device and the operator
- / Applications: High power semiconductor test

Advanced CV/IV and Low Current Arms

- / Advanced Coax/Triax measurements down to fA-level
- / Easy switching between CV and IV measurements
- / Small pad probing over a full thermal range of -60°C to 300°C with **HTS*** and unique ceramic blades
- / Applications: Highly precise device characterization and modelling, ultra-low noise measurements (1/f)

*High Thermal Stability (HTS)

High Thermal Stability (HTS) is part of FormFactor's unique Contact Intelligence Technology. A special dedicated low-thermal expansion material enables

RF/mm-Wave and Terahertz Arms

- / Ergonomic concept: completely modular
- / Lowest possible insertion loss
- / Highest raw directivity and dynamic range
- / Extremely stable calibrations
- / Available probes: ACP, Infinity, |Z| Probe, T-Wave
- / Highest accuracy and reliable data over a full thermal range of -60°C up to +175°C (depending on frequency) with **HTS***
- / **Applications:** RF, mm-Wave, terahertz probing, load-pull

extremely stable probing over time and at multiple temperatures. HTS is available for certain CV/IV, RF, mm-Wave and terahertz arms.



Probe Station Compatibility

	MPS150/ EPS150	SUMMIT	BlueRay	PM8/ EPS200	CM300xi	PA300/ PM300	TESLA	Vac/Cryo
Manual Pos	itioners							
DPP105	•	0	0	•	_	•	_	_
DPP2xx	•	•	•	•	•	•	•	-
DPP3xx	•	0	0	•	0	•	0	_
DPP450	•	0	_	0	0	0	_	_
VCP110	_	_	_	_	_	_	_	•
RPP210	•	•	•	•	•	•	•	_
RPP304	•	•	_	•	•	_	_	_
RPP305	•	0	•	•	•	•	_	_
RPP404	•	•	_	•	•	_	_	_
mmW LAP	_	•	_	•	•	0	0	_
Motorized F	Positioners							
RPP504	_	•	_	•	•	_	_	_
MS1	_	•*	_	_	_	_	_	_
PH510	_	_	•	•	0	•	_	_
SiPh	_	•**	_	_	•	_	_	_
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[•] Recommended O Possible but not recommended — Not available

*Summit12000 only **SUMMIT200 only

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